

N-channel 600 V, 0.186 Ω typ., 18 A MDmesh™ M2 Power MOSFET in a PowerFLAT™ 8x8 HV package

Datasheet - production data

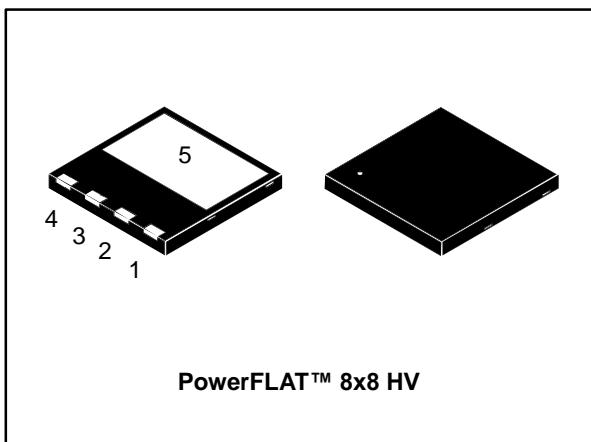
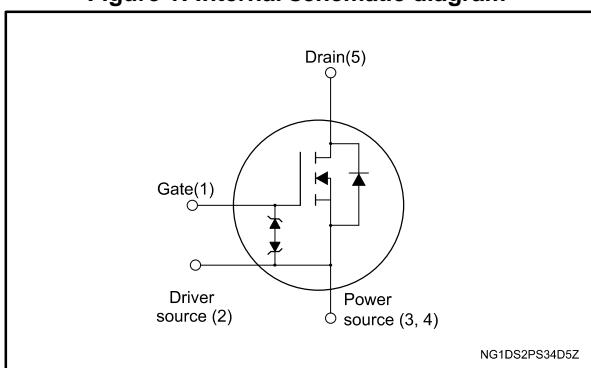


Figure 1: Internal schematic diagram



Features

Order code	V _{DS@TJ max}	R _{DS(on) max.}	I _D
STL24N60M2	650 V	0.210 Ω	18 A

- Extremely low gate charge
- Excellent output capacitance (C_{oss}) profile
- 100% avalanche tested
- Zener-protected

Applications

- Switching applications

Description

This device is an N-channel Power MOSFET developed using MDmesh™ M2 technology. Thanks to its strip layout and an improved vertical structure, the device exhibits low on-resistance and optimized switching characteristics, rendering it suitable for the most demanding high efficiency converters.

Table 1: Device summary

Order code	Marking	Package	Packing
STL24N60M2	24N60M2	PowerFLAT™ 8x8 HV	Tape and reel

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1 Electrical ratings

Table 2: Absolute maximum ratings

Symbol	Parameter	Value	Unit
V_{GS}	Gate-source voltage	± 25	V
$I_D^{(1)}$	Drain current (continuous) at $T_c = 25^\circ\text{C}$	18	A
$I_D^{(1)}$	Drain current (continuous) at $T_c = 100^\circ\text{C}$	12	A
$I_{DM}^{(1)(2)}$	Drain current (pulsed)	72	A
$P_{TOT}^{(1)}$	Total dissipation at $T_c = 25^\circ\text{C}$	125	W
$dv/dt^{(3)}$	Peak diode recovery voltage slope	15	V/ns
$dv/dt^{(4)}$	MOSFET dv/dt ruggedness	50	V/ns
T_{stg}	Storage temperature range	-55 to 150	$^\circ\text{C}$
T_j	Operating junction temperature range		

Notes:

(1)the value is limited by package

(2)Pulse width limited by safe operating area.

(3) $I_{SD} \leq 18 \text{ A}$, $di/dt \leq 400 \text{ A}/\mu\text{s}$; $V_{DS(\text{peak})} < V_{(\text{BR})DSS}$, $V_{DD} = 400 \text{ V}$.(4) $V_{DS} \leq 480 \text{ V}$

Table 3: Thermal data

Symbol	Parameter	Value	Unit
$R_{thj-case}$	Thermal resistance junction-case max	1	$^\circ\text{C}/\text{W}$
$R_{thj-pcb}^{(1)}$	Thermal resistance junction-pcb max	45	$^\circ\text{C}/\text{W}$

Notes:(1)When mounted on FR-4 board of 1cm^2 , 2oz Cu.

Table 4: Avalanche characteristics

Symbol	Parameter	Value	Unit
I_{AR}	Avalanche current, repetitive or not repetitive (pulse width limited by T_{jmax})	3.5	A
E_{AS}	Single pulse avalanche energy (starting $T_j = 25^\circ\text{C}$, $I_D = I_{AR}$; $V_{DD} = 50 \text{ V}$)	180	mJ

2 Electrical characteristics

$T_C = 25^\circ\text{C}$ unless otherwise specified

Table 5: On/off states

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$V_{(BR)DSS}$	Drain-source breakdown voltage	$V_{GS} = 0 \text{ V}$, $I_D = 1 \text{ mA}$	600			V
$I_{DS(on)}$	Zero gate voltage Drain current	$V_{GS} = 0 \text{ V}$, $V_{DS} = 600 \text{ V}$			1	μA
		$V_{GS} = 0 \text{ V}$, $V_{DS} = 600 \text{ V}$, $T_C = 125^\circ\text{C}$ ⁽¹⁾			100	μA
I_{GSS}	Gate-body leakage current	$V_{DS} = 0 \text{ V}$, $V_{GS} = \pm 25 \text{ V}$			± 10	μA
$V_{GS(th)}$	Gate threshold voltage	$V_{DS} = V_{GS}$, $I_D = 250 \mu\text{A}$	2	3	4	V
$R_{DS(on)}$	Static drain-source on-resistance	$V_{GS} = 10 \text{ V}$, $I_D = 9 \text{ A}$		0.186	0.210	Ω

Notes:

⁽¹⁾Defined by design, not subject to production test.

Table 6: Dynamic

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
C_{iss}	Input capacitance	$V_{DS} = 100 \text{ V}$, $f = 1 \text{ MHz}$, $V_{GS} = 0 \text{ V}$	-	1060	-	pF
C_{oss}	Output capacitance		-	55	-	pF
C_{rss}	Reverse transfer capacitance		-	2.2	-	pF
$C_{oss eq.}$ ⁽¹⁾	Equivalent output capacitance	$V_{DS} = 0$ to 480 V , $V_{GS} = 0 \text{ V}$	-	258	-	pF
R_G	Intrinsic gate resistance	$f = 1 \text{ MHz}$ open drain	-	7	-	Ω
Q_g	Total gate charge	$V_{DD} = 480 \text{ V}$, $I_D = 18 \text{ A}$, $V_{GS} = 10 \text{ V}$ (see Figure 15: "Gate charge test circuit")	-	29	-	nC
Q_{gs}	Gate-source charge		-	6	-	nC
Q_{gd}	Gate-drain charge		-	12	-	nC

Notes:

⁽¹⁾ $C_{oss eq.}$ is defined as a constant equivalent capacitance giving the same charging time as C_{oss} when V_{DS} increases from 0 to 80% V_{DSS}

Table 7: Switching times

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$t_{d(on)}$	Turn-on delay time	$V_{DD} = 300 \text{ V}$, $I_D = 9 \text{ A}$, $R_G = 4.7 \Omega$, $V_{GS} = 10 \text{ V}$ (see Figure 14: "Switching times test circuit for resistive load" and (Figure 19: "Switching time waveform"))	-	14	-	ns
t_r	Rise time		-	9	-	ns
$t_{d(off)}$	Turn-off delay time		-	60	-	ns
t_f	Fall time		-	15	-	ns

Table 8: Source drain diode

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$I_{SD}^{(1)}$	Source-drain current		-		18	A
$I_{SDM}^{(1)(2)}$	Source-drain current (pulsed)		-		72	A
$V_{SD}^{(3)}$	Forward on voltage	$V_{GS} = 0 \text{ V}$, $I_{SD} = 18 \text{ A}$	-		1.6	V
t_{rr}	Reverse recovery time	$I_{SD} = 18 \text{ A}$, $dI/dt = 100 \text{ A}/\mu\text{s}$, $V_{DD} = 60 \text{ V}$ (see <i>Figure 16: "Test circuit for inductive load switching and diode recovery times"</i>)	-	332		ns
Q_{rr}	Reverse recovery charge		-	4		μC
I_{RRM}	Reverse recovery current		-	24		A
t_{rr}	Reverse recovery time	$I_{SD} = 18 \text{ A}$, $dI/dt = 100 \text{ A}/\mu\text{s}$, $V_{DD} = 60 \text{ V}$, $T_j = 150 \text{ }^\circ\text{C}$ (see <i>Figure 16: "Test circuit for inductive load switching and diode recovery times"</i>)	-	450		ns
Q_{rr}	Reverse recovery charge		-	5.5		μC
I_{RRM}	Reverse recovery current		-	25		A

Notes:

(1)The value is limited by package.

(2)Pulse width is limited by safe operating area

(3)Pulsed: pulse duration = 300 μs , duty cycle 1.5%

2.1 Electrical characteristics (curves)

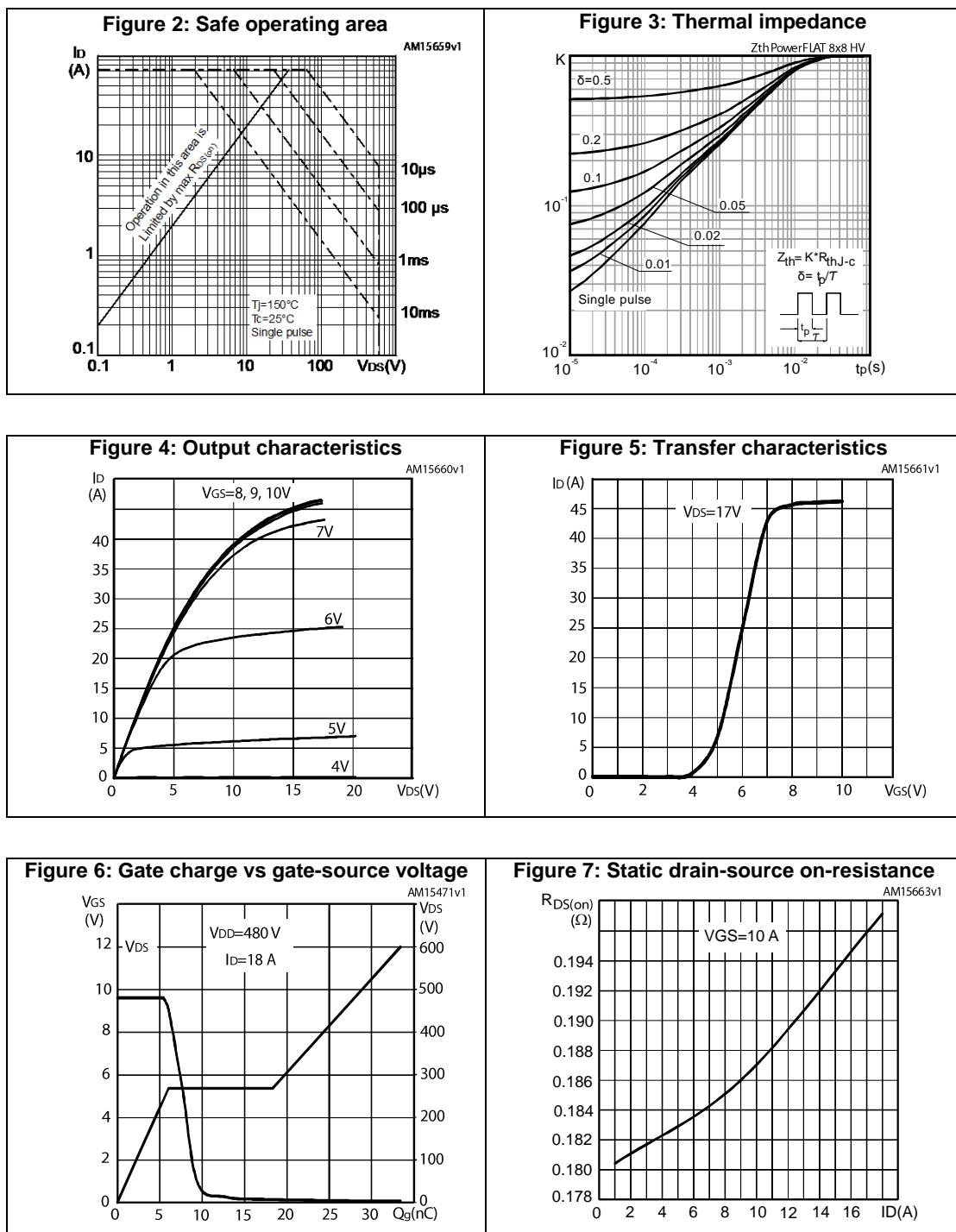
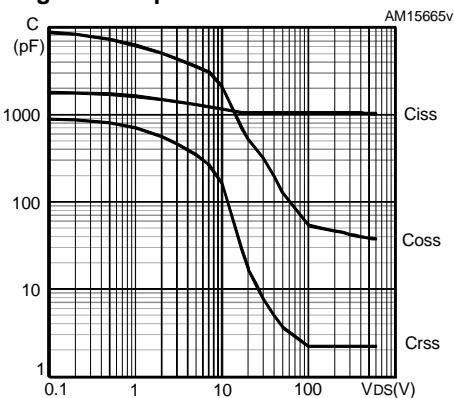
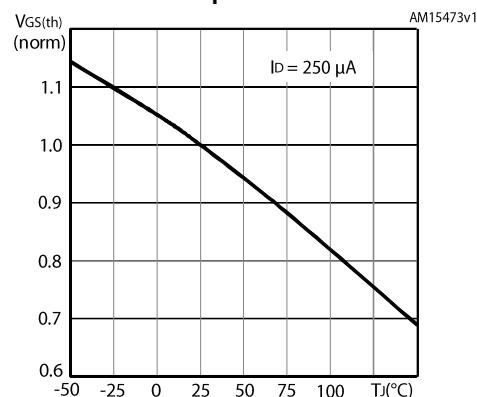
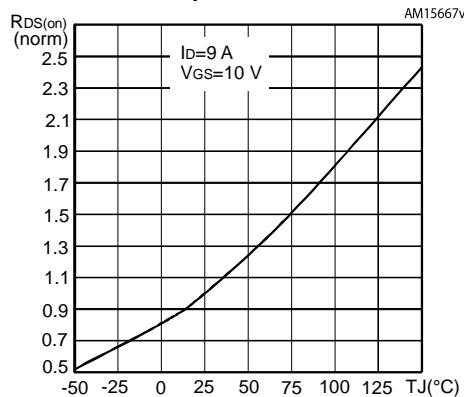
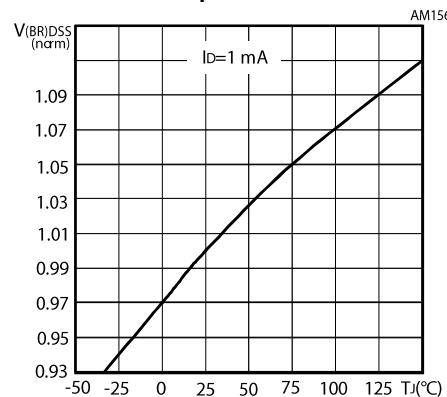
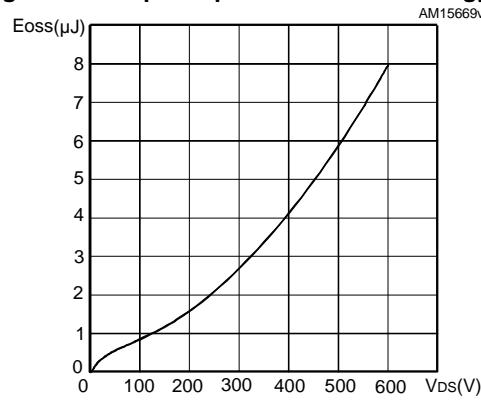
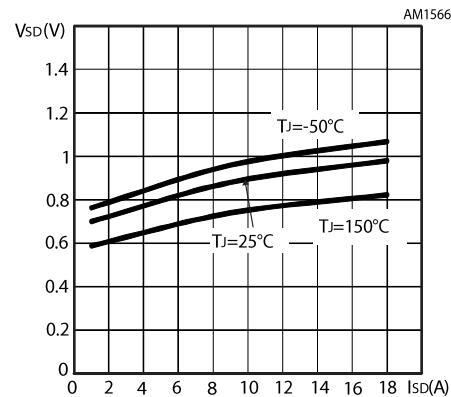
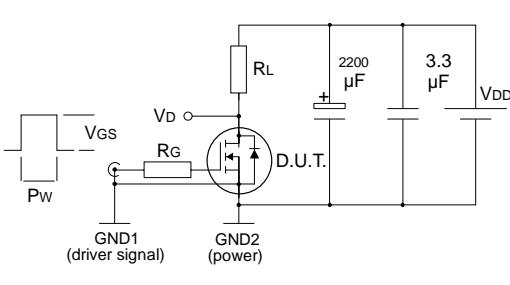


Figure 8: Capacitance variations**Figure 9: Normalized gate threshold voltage vs temperature****Figure 10: Normalized on-resistance vs temperature****Figure 11: Normalized V(BR)DSS vs temperature****Figure 12: Output capacitance stored energy****Figure 13: Source-drain diode forward characteristics**

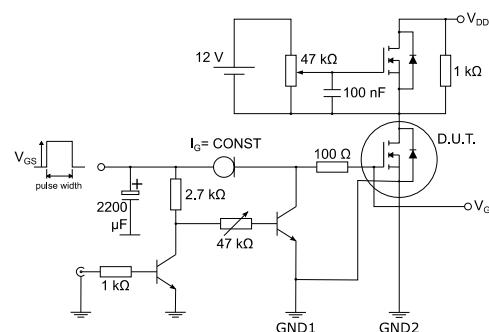
3 Test circuits

Figure 14: Switching times test circuit for resistive load



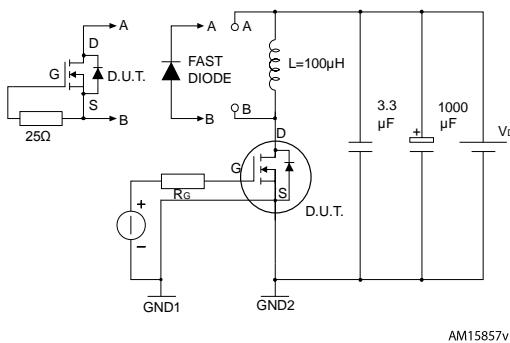
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Figure 15: Gate charge test circuit



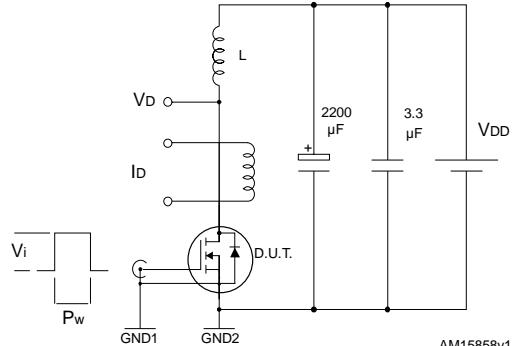
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Figure 16: Test circuit for inductive load switching and diode recovery times



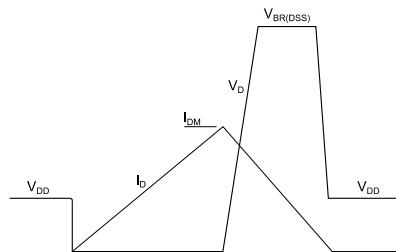
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Figure 17: Unclamped inductive load test circuit



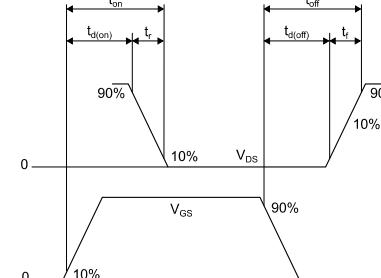
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Figure 18: Unclamped inductive waveform



AM01472v1

Figure 19: Switching time waveform



AM01473v1

4 Package information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: www.st.com.
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4.1 PowerFLAT™ 8x8 HV package information

Figure 20: PowerFLAT™ 8x8 HV package outline

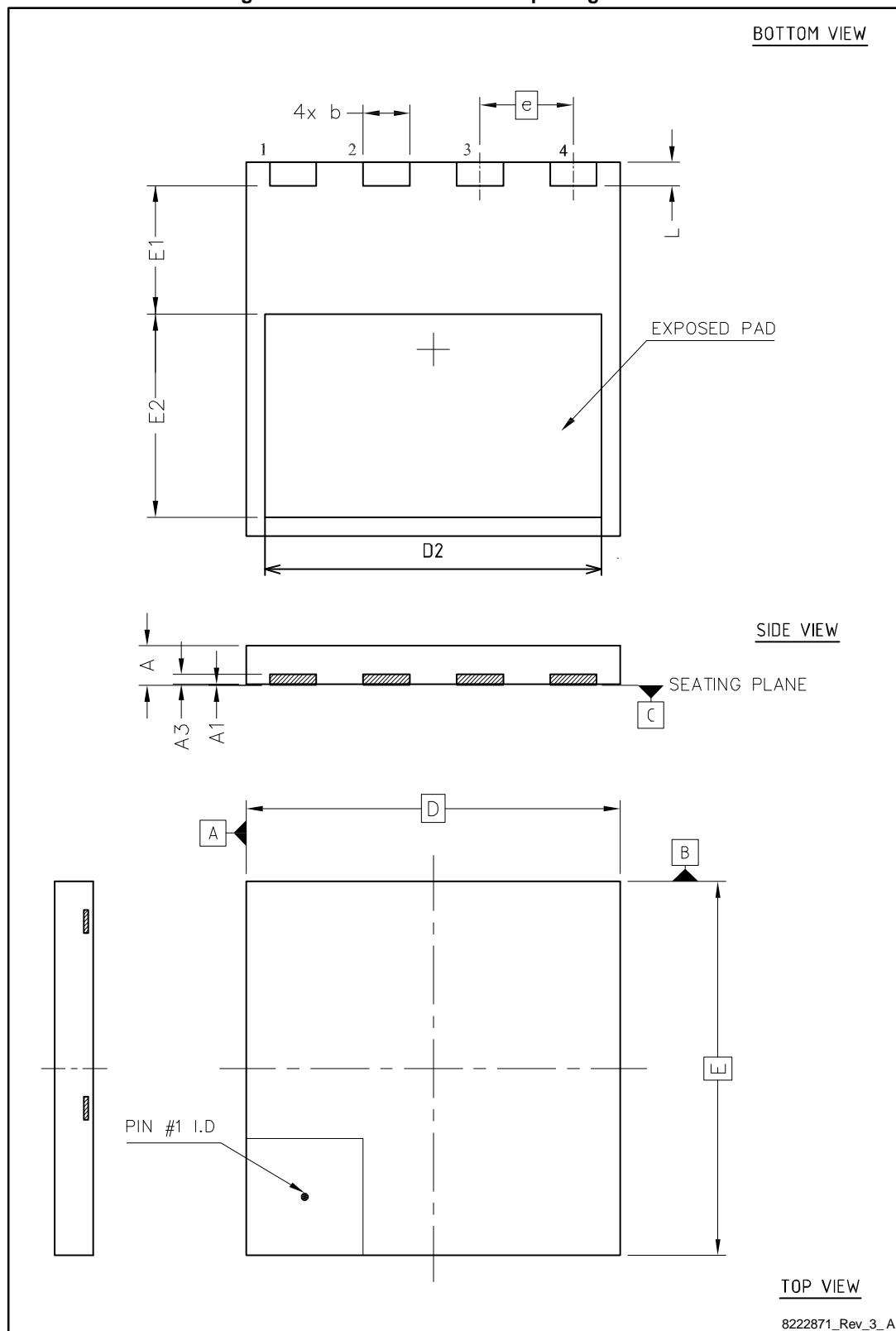
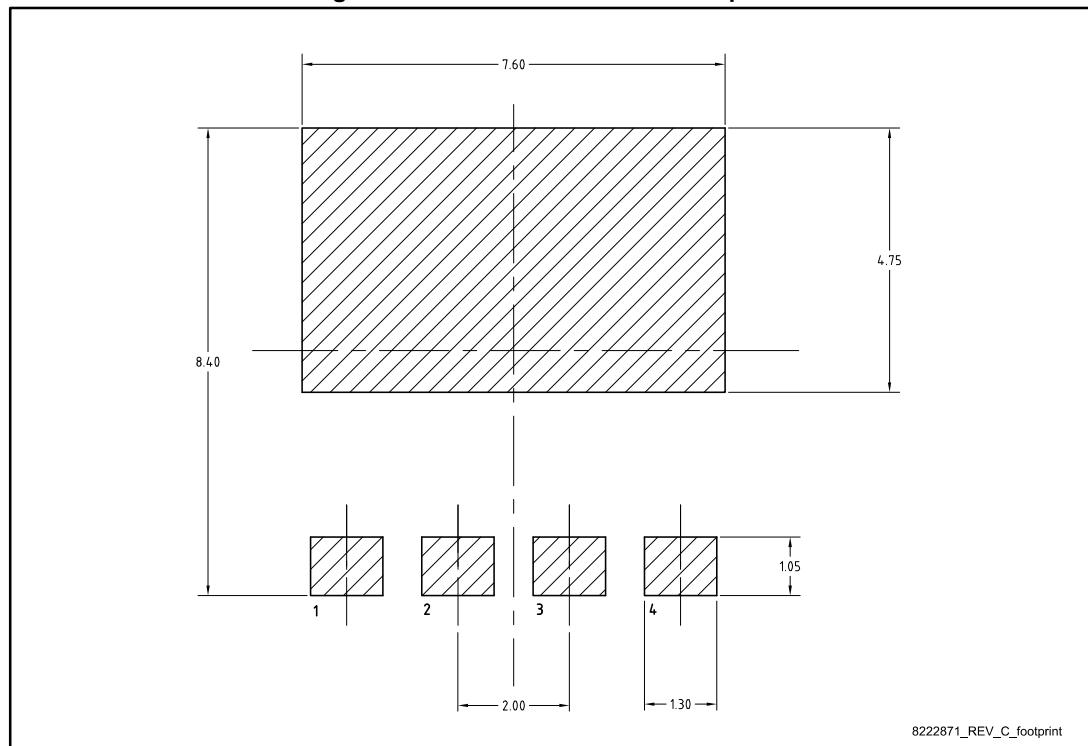


Table 9: PowerFLAT™ 8x8 HV mechanical data

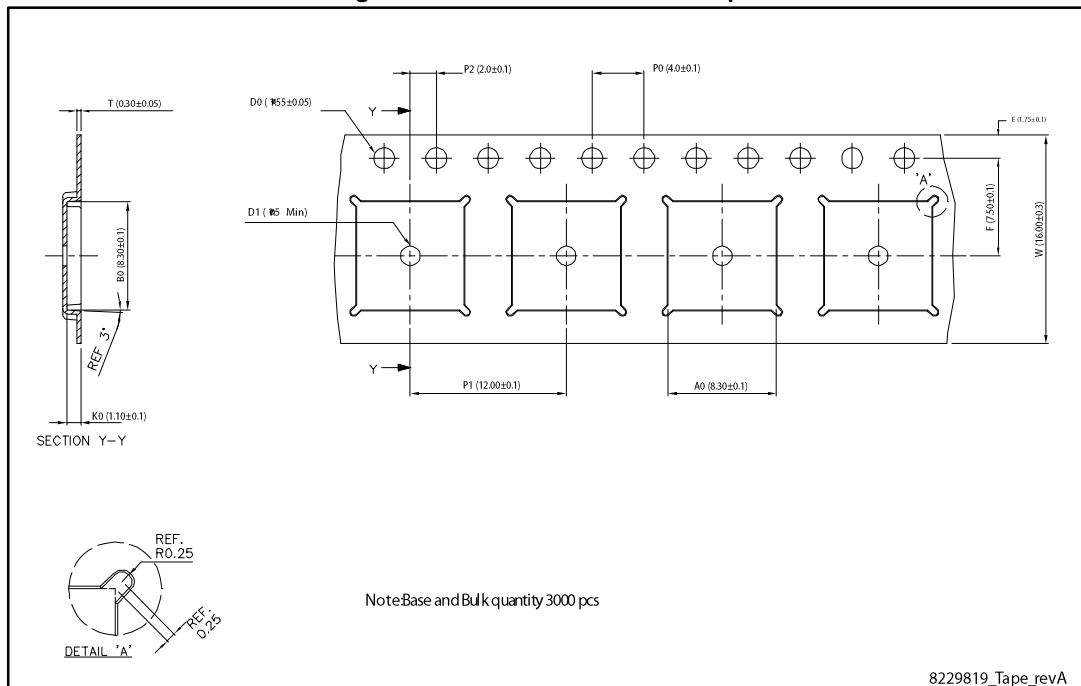
Dim.	mm		
	Min.	Typ.	Max.
A	0.75	0.85	0.95
A1	0.00		0.05
A3	0.10	0.20	0.30
b	0.90	1.00	1.10
D	7.90	8.00	8.10
E	7.90	8.00	8.10
D2	7.10	7.20	7.30
E1	2.65	2.75	2.85
E2	4.25	4.35	4.45
e		2.00	
L	0.40	0.50	0.60

Figure 21: PowerFLAT™ 8x8 HV footprint

All dimensions are in millimeters.

4.2 PowerFLAT™ 8x8 HV packing information

Figure 22: PowerFLAT™ 8x8 HV tape



All dimensions are in millimeters.

Figure 23: PowerFLAT™ 8x8 HV package orientation in carrier tape

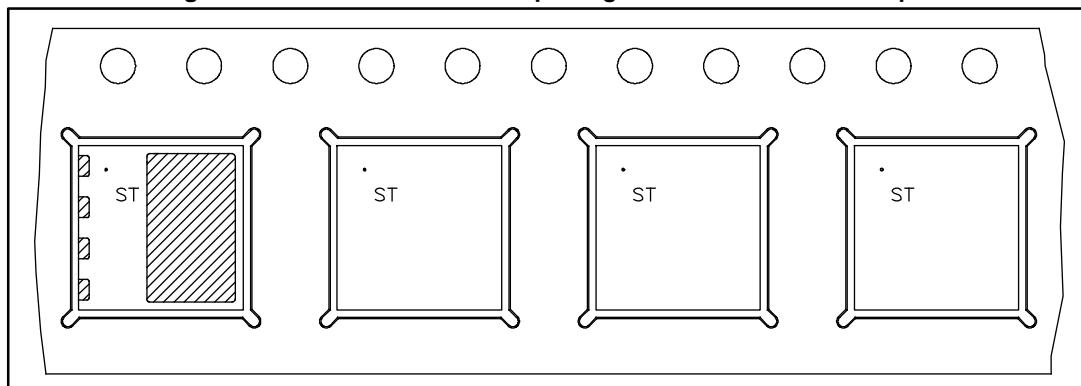
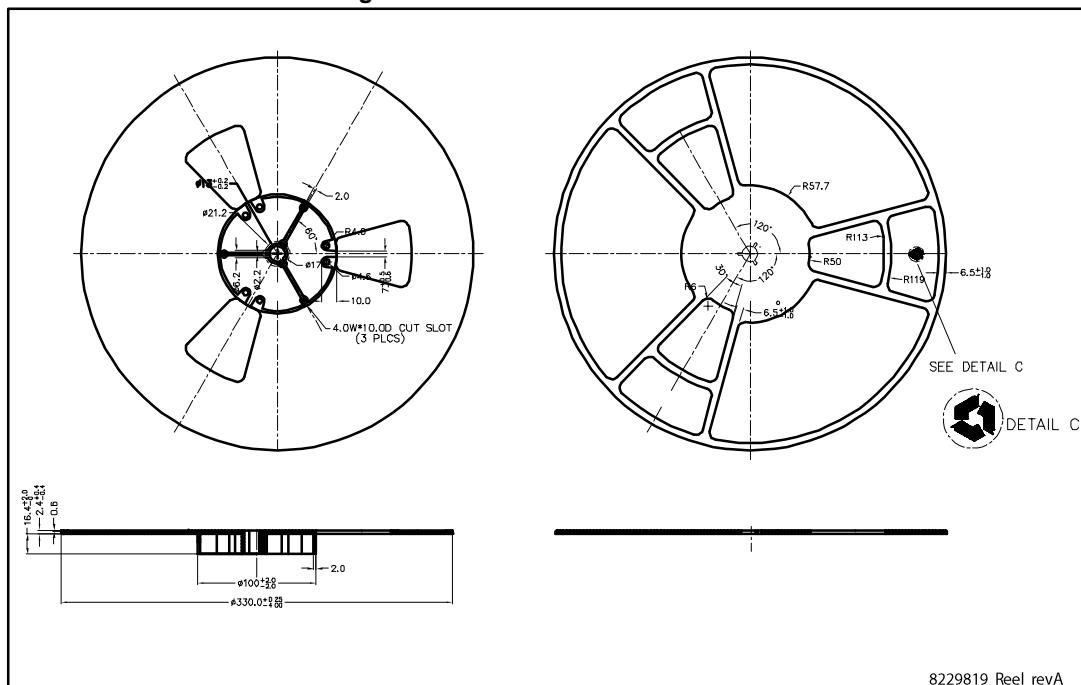


Figure 24: PowerFLAT™ 8x8 HV reel



All dimensions are in millimeters.

5 Revision history

Table 10: Document revision history

Date	Revision	Changes
11-Jun-2013	1	First release.
28-Feb-2014	2	Modified: I_D (at $T_C = 100^\circ\text{C}$) value in Table 3. Modified: V_{SD} max value, figures 3 and 11. Updated: Section 4: Package mechanical data – Minor text changes.
25-May-2016	3	Updated features and description in cover page. Updated package silhouette and Figure 1: "Internal schematic diagram" . Updated Section 4: "Test circuits" and Section 5.1: "PowerFLAT™ 8x8 HV package information" . Minor text changes

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